



PATENT
81790.0189

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Tomomi MOMOHARA

Serial No: 09/686,200 (reissue of USPN 5,818,249)

Confirmation No.: 6091

Filed: October 5, 2000

For: PROBE CARD HAVING GROUPS OF
PROBE NEEDLES IN A PROBING TEST
APPARATUS FOR TESTING
SEMICONDUCTOR INTEGRATED
CIRCUITS

Art Unit: 2829

Examiner: Nguyen, Vinh P.

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Dear Sir:

Please address all future communications regarding the above-referenced patent application to:

William H. Wright
Hogan & Hartson L.L.P.
Biltmore Tower
500 South Grand Avenue, Suite 1900
Los Angeles, California 90071
Telephone: 213-337-6700
Facsimile: 213-337-6701

It is certified that the person whose signature appears below has the authority to change the correspondence address for the above-identified application.

Respectfully submitted,

HOGAN & HARTSON L.L.P.

By:

William H. Wright

Registration No. 36,312

Attorney for Applicant(s)

Date: September 30, 2004

500 South Grand Avenue, Suite 1900
Los Angeles, California 90071
Phone: 213-337-6700
Fax: 213-337-6701